



4467-103 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of  
Zenhausen, F.

Serial No. 09/407,581

Filed: September 28, 1999

For: METHOD AND APPARATUS  
FOR MONITORING MATERIALS  
USED IN ELECTRONICS

Group Art Unit: 2857  
Examiner: Tsai, Carol S.W.

Commissioner for Patents  
Washington, D.C. 20231

SIR:

**AMENDMENT**

In response to the Office Action dated March 27, 2002, please amend the application as follows:

In the Claims:

Please amend claims 1, 6, 7, 9-13, 15-17 and 43 as follows:

1. (Amended) A method for making or monitoring an electronic device, comprising the steps of:

measuring at least one analyte selected from the group consisting of a material in the electronic device, a constituent of the material, a byproduct of the material, a reaction product of a constituent of the material, a contaminant, and a tag; the analyte is a gas, vapor, suspension in a gas or volatile organic compound;

detecting more than one physical, chemical, or physico-chemical property of the analyte;

combining the detected properties to produce a signal output; and

processing the signal output with multivariate analysis to convert the signal output into information representative of a quality of the material, a constituent of the material, or a variable in processing the material.